### **MOSFET** – Power, Single

# **N-Channel** 40 V, 0.72 mΩ, 368 A

### NTMJS0D8N04CL

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- LFPAK8 Package, Industry Standard
- These Devices are Pb-Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	40	٧
Gate-to-Source Voltage	Э		V <sub>GS</sub>	20	V
Continuous Drain	ain Steady T <sub>C</sub> = 25°C		I <sub>D</sub>	368	Α
Current R <sub>θJC</sub> (Notes 1, 3)	State	T <sub>C</sub> = 100°C		260	
Power Dissipation		T <sub>C</sub> = 25°C	$P_{D}$	180	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C	1	90	
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	56	Α
Current R <sub>θJA</sub> (Notes 1, 2, 3)	State	T <sub>A</sub> = 100°C	1	40	
Power Dissipation		T <sub>A</sub> = 25°C	$P_{D}$	4.2	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C	1	2.1	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	150	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 32.8 A)			E <sub>AS</sub>	1286	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.83	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	35.9	

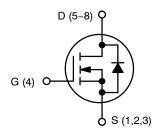
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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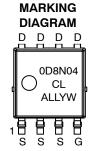
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
40 V	$0.72~\mathrm{m}\Omega$ @ $10~\mathrm{V}$	368 A
40 V	1.15 mΩ @ 4.5 V	300 A



**N-CHANNEL MOSFET** 



LFPAK8 CASE 760AA



0D8N04CL = Specific Device Code

A = Assembly Location LL = Wafer Lot

Y = Year
W = Work Week

#### ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				18		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			10	μΑ
		$V_{GS} = 0 \text{ V},$ $V_{DS} = 40 \text{ V}$	T <sub>J</sub> = 125°C			250	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	s = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \mu A$		1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.7		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		0.60	0.72	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 50 A		0.91	1.15	
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> =15 V, I <sub>D</sub>	= 50 A		500		S
CHARGES, CAPACITANCES & GATE RES	SISTANCE						
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 25 V			9600		pF
Output Capacitance	C <sub>OSS</sub>				4690		
Reverse Transfer Capacitance	C <sub>RSS</sub>				119		
Total Gate Charge	$Q_{G(TOT)}$	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 32 V; I <sub>D</sub> = 50 A			78		nC
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 32 V; I <sub>D</sub> = 50 A			162		1
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 32 V; I <sub>D</sub> = 50 A			14		1
Gate-to-Source Charge	$Q_{GS}$				25		
Gate-to-Drain Charge	$Q_{GD}$				29		
Plateau Voltage	$V_{GP}$				2.7		V
SWITCHING CHARACTERISTICS (Note 5)							
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 32 \text{ V},$ $I_{D} = 50 \text{ A}, R_{G} = 2.5 \Omega$			36		ns
Rise Time	t <sub>r</sub>				50		1
Turn-Off Delay Time	t <sub>d(OFF)</sub>				81		
Fall Time	t <sub>f</sub>				37		
DRAIN-SOURCE DIODE CHARACTERIST	rics						
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$		0.73	1.2	V
		I <sub>S</sub> = 50 A	T <sub>J</sub> = 125°C		0.6		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			83		ns
Charge Time	ta				53		1
Discharge Time	t <sub>b</sub>				30		1
Reverse Recovery Charge	Q <sub>RR</sub>				163		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

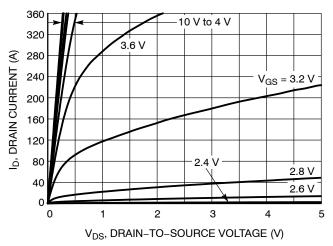


Figure 1. On-Region Characteristics

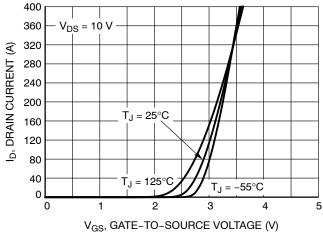


Figure 2. Transfer Characteristics

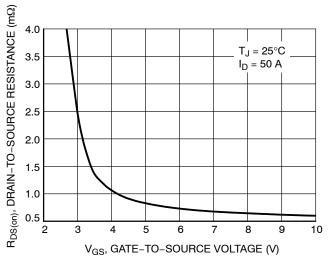


Figure 3. On-Resistance vs. Gate-to-Source Voltage

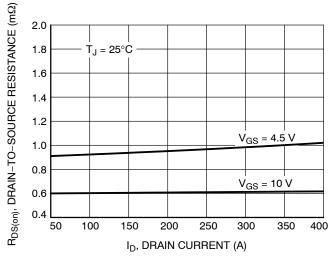


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

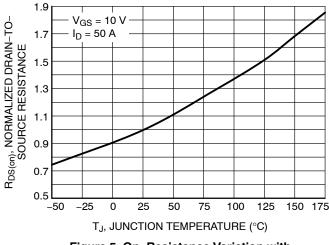


Figure 5. On–Resistance Variation with Temperature

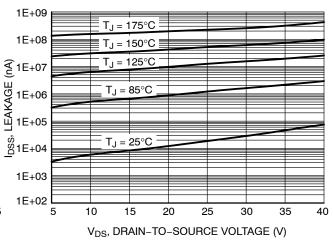


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

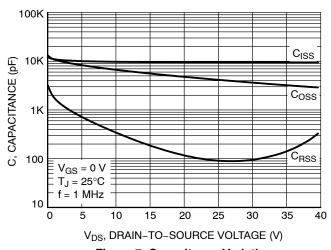


Figure 7. Capacitance Variation

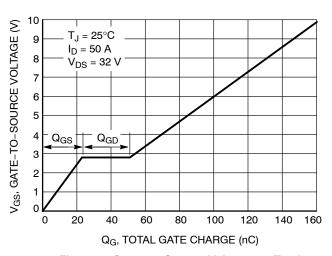


Figure 8. Gate-to-Source Voltage vs. Total Charge

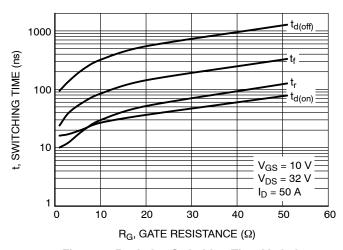


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

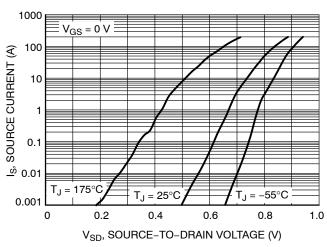


Figure 10. Diode Forward Voltage vs. Current

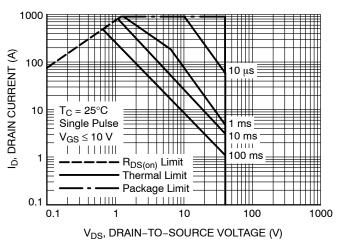


Figure 11. Maximum Rated Forward Biased Safe Operating Area

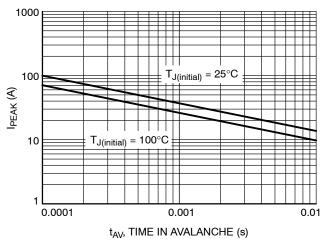


Figure 12. Maximum Drain Current vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

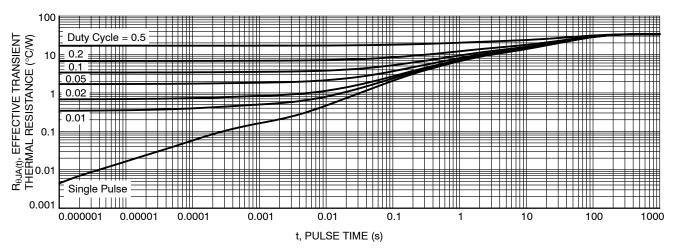
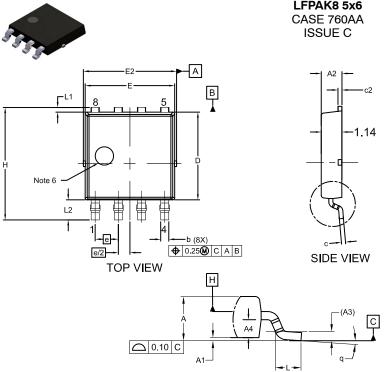


Figure 13. Transient Thermal Impedance

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTMJS0D8N04CLTWG	0D8N04CL	LFPAK8 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



## LFPAK8 5x6

**DATE 13 AUG 2019** 

#### NOTES:

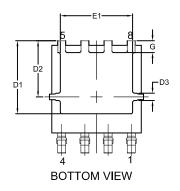
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M. 1994.
- CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- DIMENSIONS D AND E ARE **DETERMINED AT THE OUTERMOST** EXTREMES OF THE PLASTIC BODY.
- DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

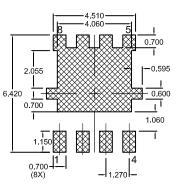
NAUL LINAETERO

OPTIONAL MOLD FEATURE.

MILLIMETERS				
DIM	MIN	NOM	MAX	
Α	1.10	1.20	1.30	
A1	0.00	0.08	0.15	
A2	1.10	1.15	1.20	
A3	(	).25 REF	=	
A4	0.45	0.50	0.55	
b	0.40	0.45	0.50	
С	0.19	0.22	0.25	
c2	0.19	0.22	0.25	
D	4.70	4.80	4.90	
D1	3.80	4.00	4.20	
D2	3.00	3.10	3.20	
D3	0.30	0.40	0.50	
Е	4.80	4.90	5.00	
E1	3.90	4.00	4.10	
E2	5.00	5.15	5.30	
е		1.27 BS	С	
G	0.55	0.65	0.75	
Н	6.00	6.15	6.30	
L	0.45	0.65	0.85	
L1	0.15	0.25	0.35	
L2	0.90	1.10	1.30	
q	0°	4°	8°	

#### DETAIL 'A'

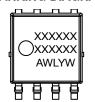




#### RECOMMENDED LAND PAD

\*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

#### **GENERIC MARKING DIAGRAM\***



XXXXXX = Specific Device Code

= Assembly Location

= Wafer Lot WL Υ = Year W = Work Week

\*This information is generic. Please refer to device data sheet for actual part marking. Some products may not follow the Generic Marking.

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